

SN74SSTVF16859

13-BIT TO 26-BIT REGISTERED BUFFER WITH SSTL_2 INPUTS AND OUTPUTS

SCES429B – MARCH 2003 – REVISED FEBRUARY 2004

- Member of the Texas Instruments Widebus™ Family
- Operates at 2.3 V to 2.7 V for PC1600, PC2100, and PC2700
- Operates at 2.5 V to 2.7 V for PC3200 (QFN Package)
- Pinout and Functionality Compatible With JEDEC Standard SSTV16859
- 600 ps Faster (Simultaneous Switching) Than the JEDEC Standard SSTV16859 in PC2700 DIMM Applications
- 1-to-2 Outputs to Support Stacked DDR DIMMs
- Output Edge-Control Circuitry Minimizes Switching Noise in an Unterminated Line
- Outputs Meet SSTL_2 Class I Specifications
- Supports SSTL_2 Data Inputs
- Differential Clock (CLK and $\overline{\text{CLK}}$) Inputs
- Supports LVCMOS Switching Levels on the $\overline{\text{RESET}}$ Input
- $\overline{\text{RESET}}$ Input Disables Differential Input Receivers, Resets All Registers, and Forces All Outputs Low
- Pinout Optimizes DIMM PCB Layout
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)

DGG PACKAGE
(TOP VIEW)

Q13A	1	64	V _{DDQ}
Q12A	2	63	GND
Q11A	3	62	D13
Q10A	4	61	D12
Q9A	5	60	V _{CC}
V _{DDQ}	6	59	V _{DDQ}
GND	7	58	GND
Q8A	8	57	D11
Q7A	9	56	D10
Q6A	10	55	D9
Q5A	11	54	GND
Q4A	12	53	D8
Q3A	13	52	D7
Q2A	14	51	$\overline{\text{RESET}}$
GND	15	50	GND
Q1A	16	49	$\overline{\text{CLK}}$
Q13B	17	48	CLK
V _{DDQ}	18	47	V _{DDQ}
Q12B	19	46	V _{CC}
Q11B	20	45	V _{REF}
Q10B	21	44	D6
Q9B	22	43	GND
Q8B	23	42	D5
Q7B	24	41	D4
Q6B	25	40	D3
GND	26	39	GND
V _{DDQ}	27	38	V _{DDQ}
Q5B	28	37	V _{CC}
Q4B	29	36	D2
Q3B	30	35	D1
Q2B	31	34	GND
Q1B	32	33	V _{DDQ}

description/ordering information

This 13-bit to 26-bit registered buffer is designed for 2.3-V to 2.7-V V_{CC} operation.

ORDERING INFORMATION

T _A	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
0°C to 70°C	QFN – RGQ (Tin-Pb Finish)	Tape and reel	SN74SSTVF16859SR	SSF859
	QFN – RGQ (Matte-Tin Finish)		SN74SSTVF16859S8	
	TSSOP – DGG	Tape and reel	SN74SSTVF16859GR	SSTVF16859

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



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SN74SSTVF16859
13-BIT TO 26-BIT REGISTERED BUFFER
WITH SSTL_2 INPUTS AND OUTPUTS

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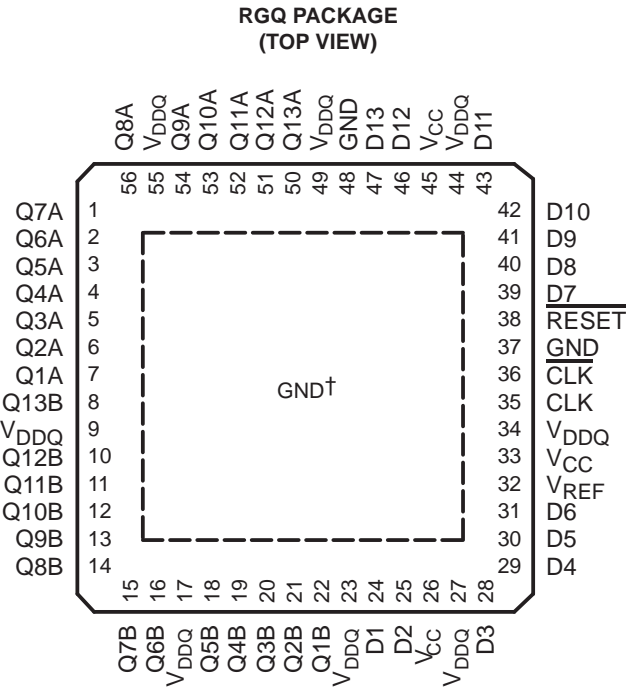
description/ordering information (continued)

All inputs are SSTL_2, except the LVCMOS reset (RESET) input. All outputs are edge-controlled LVCMOS circuits optimized for unterminated DIMM loads.

The SN74SSTVF16859 operates from a differential clock (CLK and CLK). Data are registered at the crossing of CLK going high and CLK going low.

The device supports low-power standby operation. When RESET is low, the differential input receivers are disabled, and undriven (floating) data, clock, and reference voltage (VREF) inputs are allowed. In addition, when RESET is low, all registers are reset and all outputs are forced low. The LVCMOS RESET input always must be held at a valid logic high or low level.

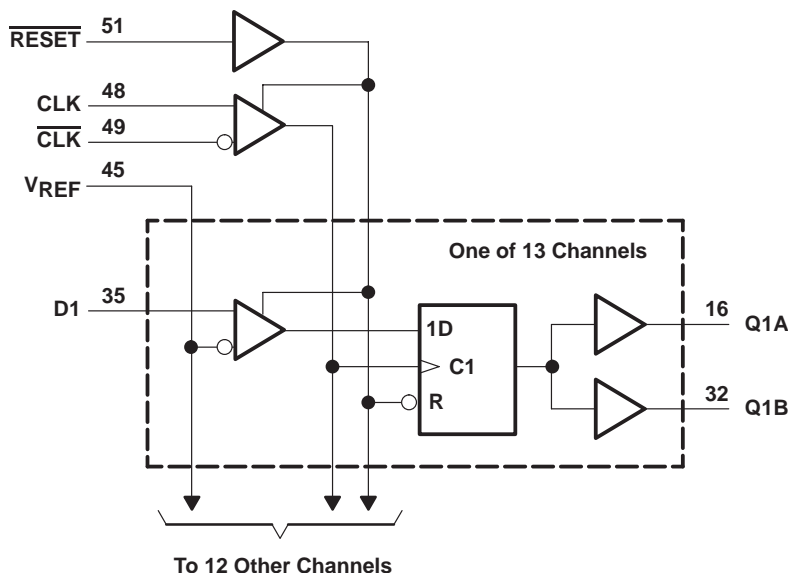
To ensure defined outputs from the register before a stable clock has been supplied, RESET must be held in the low state during power up.



† The center die pad must be connected to GND.

Table with 5 columns: INPUTS (RESET, CLK, CLK, D) and OUTPUT (Q). It shows the output state for different combinations of input states (High, Low, or floating).

logic diagram (positive logic)



Pin numbers shown are for the DGG package.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} or V_{DDQ}	–0.5 V to 3.6 V
Input voltage range, V_I (see Notes 1 and 2)	–0.5 V to $V_{CC} + 0.5$ V
Output voltage range, V_O (see Notes 1 and 2)	–0.5 V to $V_{DDQ} + 0.5$ V
Input clamp current, I_{IK} ($V_I < 0$)	–50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{DDQ}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{DDQ})	±50 mA
Continuous current through each V_{CC} , V_{DDQ} , or GND	±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DGG package	55°C/W
(see Note 4): RGQ package	22°C/W
Storage temperature range, T_{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. This value is limited to 3.6 V maximum.
 3. The package thermal impedance is calculated in accordance with JESD 51-7.
 4. The package thermal impedance is calculated in accordance with JESD 51-5.

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WITH SSTL 2 INPUTS AND OUTPUTS

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recommended operating conditions (see Note 5)

			MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage		V _{DDQ}		2.7	V
V _{DDQ}	Output supply voltage	PC1600, PC2100, PC2700	2.3		2.7	V
		PC3200	2.5		2.7	
V _{REF}	Reference voltage (V _{REF} = V _{DDQ} /2)	PC1600, PC2100, PC2700	1.15	1.25	1.35	V
		PC3200	1.25	1.3	1.35	
V _I	Input voltage		0		V _{CC}	V
V _{IH}	AC high-level input voltage	Data inputs	V _{REF} +310mV			V
V _{IL}	AC low-level input voltage	Data inputs	V _{REF} −310mV			V
V _{IH}	DC high-level input voltage	Data inputs	V _{REF} +150mV			V
V _{IL}	DC low-level input voltage	Data inputs	V _{REF} −150mV			V
V _{IH}	High-level input voltage	RESET	1.7			V
V _{IL}	Low-level input voltage	RESET	0.7			V
V _{ICR}	Common-mode input voltage range	CLK, CLK	0.97		1.53	V
V _{I(PP)}	Peak-to-peak input voltage	CLK, CLK	360			mV
I _{OH}	High-level output current		−16			mA
I _{OL}	Low-level output current		16			
T _A	Operating free-air temperature		0		70	°C

NOTE 5: The $\overline{\text{RESET}}$ input of the device must be held at valid logic voltage levels (not floating) to ensure proper device operation. The differential inputs must not be floating unless $\overline{\text{RESET}}$ is low. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics for PC1600, PC2100, and PC2700 over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		V _{CC} [†]	MIN	TYP [‡]	MAX	UNIT	
V _{IK}		I _I = −18 mA		2.3 V			−1.2	V	
V _{OH}		I _{OH} = −100 μA		2.3 V to 2.7 V	V _{DDQ} −0.2			V	
		I _{OH} = −8 mA		2.3 V	1.95				
V _{OL}		I _{OL} = 100 μA		2.3 V to 2.7 V	0.2			V	
		I _{OL} = 8 mA		2.3 V	0.35				
I _I	All inputs	V _I = V _{CC} or GND		2.7 V			±5	μA	
I _{CC}	Static standby	RESET = GND		2.7 V			10	μA	
	Static operating	RESET = V _{CC} ; V _I = V _{IH} (AC) or V _{IL} (AC)					25	mA	
I _{CCD}	Dynamic operating – clock only	RESET = V _{CC} ; V _I = V _{IH} (AC) or V _{IL} (AC), CLK and CLK switching 50% duty cycle		2.5 V		19		μA/ MHz	
	Dynamic operating – per each data input	RESET = V _{CC} ; V _I = V _{IH} (AC) or V _{IL} (AC), CLK and CLK switching 50% duty cycle, One data input switching at one-half clock frequency, 50% duty cycle				7		μA/ clock MHz/ D input	
C _i [§]	Data inputs	V _I = V _{REF} ± 310 mV		2.5 V		2.5	3	3.5	pF
	CLK, CLK	V _{ICR} = 1.25 V, V _I (PP) = 360mV				2.5	3	3.5	
	RESET	V _I = V _{CC} or GND				2.3	3	3.5	

† For this test condition, V_{DDQ} always is equal to V_{CC} .

‡ All typical values are at $V_{CC} = 2.5\text{ V}$, $T_A = 25^\circ\text{C}$.

§ Measured at 50-MHz input frequency



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electrical characteristics for PC3200 over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC} [†]	MIN	TYP [‡]	MAX	UNIT
V _{IK}		I _I = –18 mA	2.5 V			–1.2	V
V _{OH}		I _{OH} = –100 µA	2.5 V to 2.7 V	V _{DDQ} –0.2			V
		I _{OH} = –8 mA	2.5 V	1.95			
V _{OL}		I _{OL} = 100 µA	2.5 V to 2.7 V			0.2	V
		I _{OL} = 8 mA	2.5 V			0.35	
I _I	All inputs	V _I = V _{CC} or GND	2.7 V			±5	µA
I _{CC}	Static standby	RESET = GND	2.7 V			10	µA
	Static operating	RESET = V _{CC} , V _I = V _{IH} (AC) or V _{IL} (AC)				25	mA
I _{CCD}	Dynamic operating – clock only	RESET = V _{CC} , V _I = V _{IH} (AC) or V _{IL} (AC), CLK and CLK switching 50% duty cycle	2.6 V			19	µA/MHz
	Dynamic operating – per each data input	RESET = V _{CC} , V _I = V _{IH} (AC) or V _{IL} (AC), CLK and CLK switching 50% duty cycle, One data input switching at one-half clock frequency, 50% duty cycle				7	µA/clock MHz/D input
C _i [§]	Data inputs	V _I = V _{REF} ± 310 mV	2.6 V	2.5	3	3.5	pF
	CLK, CLK	V _{ICR} = 1.25 V, V _I (PP) = 360mV		2.5	3	3.5	
	RESET	V _I = V _{CC} or GND		2.3	3	3.5	

[†] For this test condition, V_{DDQ} always is equal to V_{CC}.

[‡] All typical values are at V_{CC} = 2.6 V, T_A = 25°C.

[§] Measured at 50-MHz input frequency

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			V _{CC} = 2.5 V ± 0.2 V [†]		V _{CC} = 2.6 V ± 0.1 V [†]		UNIT
			MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		500		500		MHz
t _w	Pulse duration, CLK, CLK high or low		1		1		ns
t _{act}	Differential inputs active time (see Note 6)		22		22		ns
t _{inact}	Differential inputs inactive time (see Note 7)		22		22		ns
t _{su}	Setup time	Fast slew rate (see Notes 8 and 10)	Data before CLK↑, CLK↓		0.65	0.65	ns
		Slow slew rate (see Notes 9 and 10)			0.75	0.75	
t _h	Hold time	Fast slew rate (see Notes 8 and 10)	Data after CLK↑, CLK↓		0.65	0.65	ns
		Slow slew rate (see Notes 9 and 10)			0.8	0.8	

[†] For this test condition, V_{DDQ} always is equal to V_{CC}.

- NOTES: 6. V_{REF} must be held at a valid input level, and data inputs must be held low for a minimum time of t_{act} max, after RESET is taken high.
7. V_{REF}, data, and clock inputs must be held at valid voltage levels (not floating) for a minimum time of t_{inact} max, after RESET is taken low.
8. For data signal input slew rate ≥ 1 V/ns.
9. For data signal input slew rate ≥ 0.5 V/ns and < 1 V/ns.
10. CLK, CLK signals input slew rates are ≥ 1 V/ns.

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WITH SSTL 2 INPUTS AND OUTPUTS

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switching characteristics for TSSOP over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}^\dagger$		UNIT
			MIN	MAX	
f_{\max}			500		MHz
t_{pd}^\ddagger	CLK and $\overline{\text{CLK}}$	Q	1.1	2.5	ns
t_{PHL}	$\overline{\text{RESET}}$	Q		5	ns

[†] For this test condition, V_{DDQ} always is equal to V_{CC} .

[‡] Single-bit switching

switching characteristics for QFN over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}^\dagger$		$V_{CC} = 2.6\text{ V}$ $\pm 0.1\text{ V}^\dagger$		UNIT
			MIN	MAX	MIN	MAX	
f_{\max}			500		500		MHz
t_{pd}^\ddagger	CLK and $\overline{\text{CLK}}$	Q	1.1	2.5	1.1	2.2	ns
t_{PHL}	$\overline{\text{RESET}}$	Q		5		5	ns

[†] For this test condition, V_{DDQ} always is equal to V_{CC} .

[‡] Single-bit switching

output slew rates over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO	$V_{CC} = 2.5\text{ V}$ $\pm 0.2\text{ V}^\dagger$		$V_{CC} = 2.6\text{ V}$ $\pm 0.1\text{ V}^\dagger$		UNIT
			MIN	MAX	MIN	MAX	
dV/dt_r	20%	80%	1	4	1	4	V/ns
dV/dt_f	80%	20%	1	4	1	4	V/ns
dV/dt_{Δ}^\S	20% or 80%	80% or 20%		1		1	V/ns

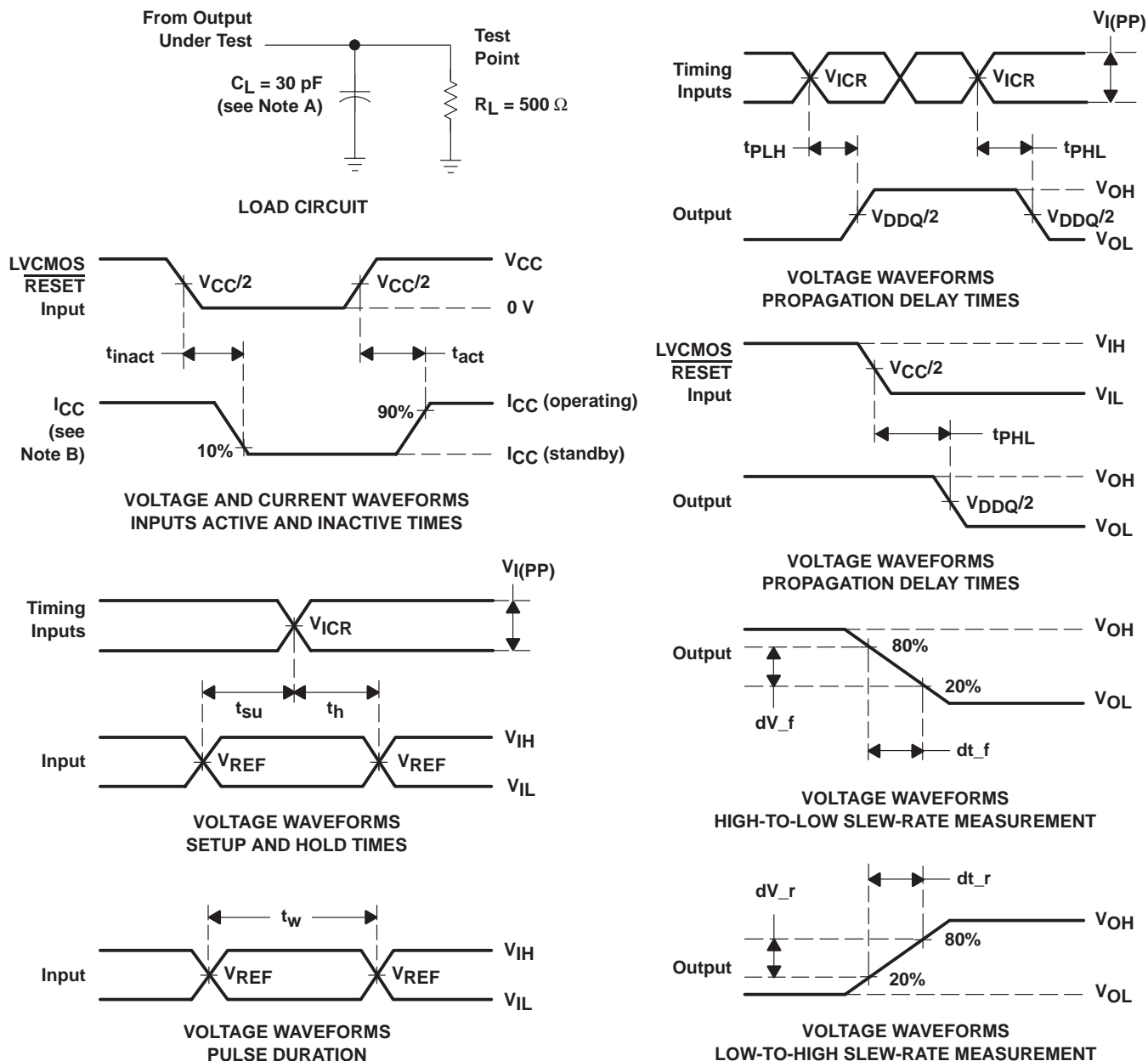
[†] For this test condition, V_{DDQ} always is equal to V_{CC} .

[§] Difference between dV/dt_r (rising edge rate) and dV/dt_f (falling edge rate).



PARAMETER MEASUREMENT INFORMATION

$V_{CC} = 2.5\text{ V} \pm 0.2\text{ V}$ AND $V_{CC} = 2.6\text{ V} \pm 0.1\text{ V}$



- NOTES:
- A. C_L includes probe and jig capacitance.
 - B. I_{CC} tested with clock and data inputs held at V_{CC} or GND, and $I_O = 0\text{ mA}$.
 - C. All input pulses are supplied by generators having the following characteristics: PRR $\leq 10\text{ MHz}$, $Z_O = 50\ \Omega$, input slew rate $= 1\text{ V/ns} \pm 20\%$ (unless otherwise noted).
 - D. The outputs are measured one at a time, with one transition per measurement.
 - E. $V_{TT} = V_{REF} = V_{DDQ}/2$
 - F. $V_{IH} = V_{REF} + 310\text{ mV}$ (ac voltage levels) for differential inputs. $V_{IH} = V_{CC}$ for LVC MOS input.
 - G. $V_{IL} = V_{REF} - 310\text{ mV}$ (ac voltage levels) for differential inputs. $V_{IL} = \text{GND}$ for LVC MOS input.
 - H. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
SN74SSTVF16859G4R	Obsolete	Production	VQFN (RGQ) 56	-	-	Call TI	Call TI	0 to 70	SSF859
SN74SSTVF16859GR	Active	Production	TSSOP (DGG) 64	2000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	0 to 70	SSTVF16859
SN74SSTVF16859S8	Obsolete	Production	VQFN (RGQ) 56	-	-	Call TI	Call TI	0 to 70	SSF859

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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TAPE AND REEL INFORMATION



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74SSTVF16859GR	TSSOP	DGG	64	2000	330.0	24.4	8.4	17.3	1.7	12.0	24.0	Q1

TAPE AND REEL BOX DIMENSIONS

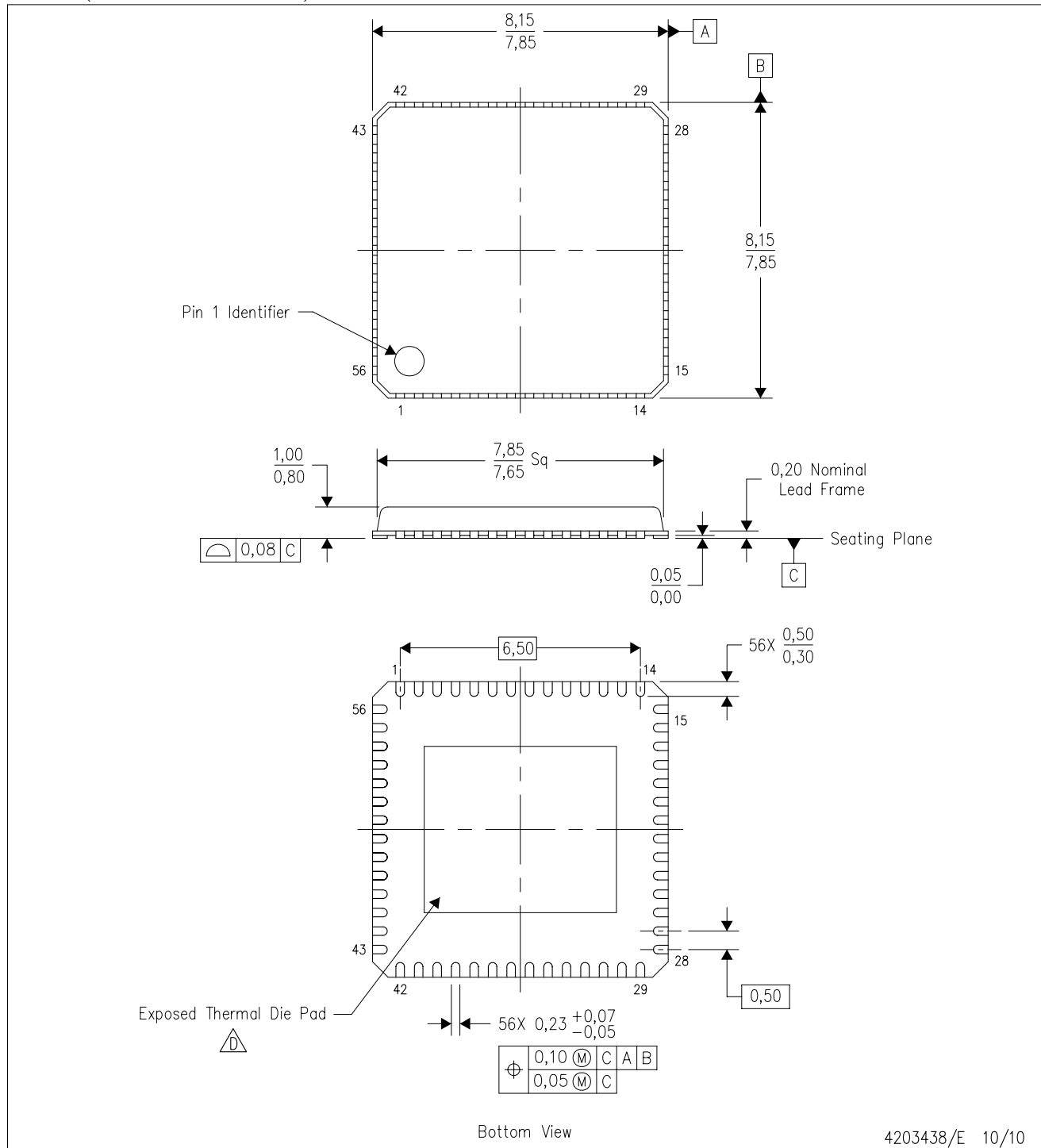


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74SSTVF16859GR	TSSOP	DGG	64	2000	356.0	356.0	45.0

RGQ (S-PVQFN-N56)

PLASTIC QUAD FLATPACK NO-LEAD



4203438/E 10/10

- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. QFN (Quad Flatpack No-Lead) Package configuration.
 - The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.
 - E. Package complies to JEDEC MO-220 variation VLLD-2.

DGG (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

48 PINS SHOWN



- NOTES: A. All linear dimensions are in millimeters.
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold protrusion not to exceed 0,15.
 D. Falls within JEDEC MO-153

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